TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3- μ s QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

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- **Controlled Baseline**
 - One Assembly
 - One Test Site
 - One Fabrication Site
- **Extended Temperature Performance of** -55°C to 125°C
- **Enhanced Diminishing Manufacturing** Sources (DMS) Support
- **Enhanced Product-Change Notification**
- Qualification Pedigree†
- Four 12-Bit Digital-to-Analog Converters
- Programmable Settling Time of Either 3 µs or 9 μs (Typ)
- TMS320™ DSP Family, (Q)SPI™, and Microwire™ Compatible Serial Interface
- **Internal Power-On Reset**
- Low Power Consumption: 8 mW, Slow Mode - 5-V Supply 3.6 mW, Slow Mode - 3-V Supply
- **Reference Input Buffer**
- **Voltage Output Range . . . 2× the Reference** Input Voltage

description

The TLV5614 is a quadruple 12-bit voltage output digital-to-analog converter (DAC) with a flexible four-wire serial interface. The four-wire serial interface allows glueless interface to TMS320™ DSP family, SPI™, QSPI™, and Microwire™ serial ports. The TLV5614 is programmed with a 16-bit serial word comprised of a DAC address, individual DAC control bits, and a 12-bit DAC value. The device has provision for two supplies - one digital supply for the serial interface (via pins DV_{DD} and DGND), and one for the DACs,

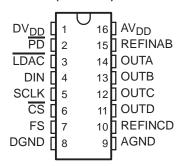
- **Monotonic Overtemperature**
- **Dual 2.7-V to 5.5-V Supply (Separate Digital** and Analog Supplies)
- Hardware Power Down (10 nA)
- Software Power Down (10 nA)
- Simultaneous Update

applications

- **Battery-Powered Test Instruments**
- **Digital Offset and Gain Adjustment**
- **Industrial Process Controls**
- **Machine and Motion Control Devices**
- Communications
- **Arbitrary Waveform Generation**

† Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

PW PACKAGE (TOP VIEW)



reference buffers, and output buffers (via pins AV_{DD} and AGND). Each supply is independent of the other and can be any value between 2.7 V and 5.5 V. The dual supplies allow a typical application where the DAC is controlled via a microprocessor operating on a 3-V supply (also used on pins DV_{DD} and DGND), with the DACs operating on a 5-V supply. The digital and analog supplies can be tied together.



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TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3-μs QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

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description (continued)

The resistor string output voltage is buffered by a 2× gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. A rail-to-rail output stage and a power-down mode makes it ideal for single-voltage, battery-based applications. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFINAB and REFINCD terminals to reduce the need for a low source-impedance drive to the terminal. REFINAB and REFINCD allow DAC A and B to have a different reference voltage than DAC C and D.

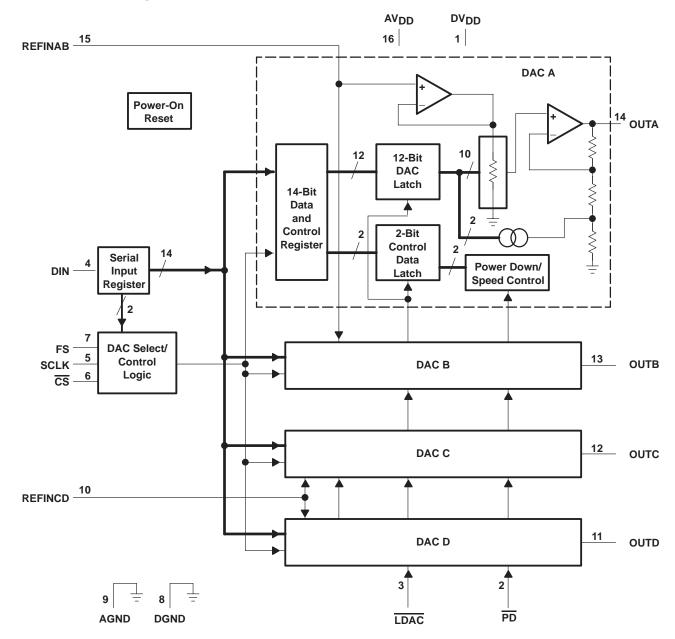
The TLV5614 is implemented with a CMOS process and is available in a 16-terminal TSSOP package. The TLV5614M is characterized for operation from -55°C to 125°C.

AVAILABLE OPTIONS

	PACKAGE
IA	TSSOP (PW)
-55°C to 125°C	TLV5614MPWREP



functional block diagram



Terminal Functions

TERMIN	IAL		DECODIFICAL.
NAME	NO.	1/0	DESCRIPTION
AGND	9		Analog ground
AV_{DD}	16		Analog supply
CS	6	1	Chip select. This terminal is active low.
DGND	8		Digital ground
DIN	4	I	Serial data input
DV_{DD}	1		Digital supply
FS	7	I	Frame synchronization. The falling edge of the frame synchronization pulse indicates the start of a serial data frame shifted out to the TLV5614.
PD	2	I	Power down. Powers down all DACs (overriding their individual power down settings) and all output stages. This terminal is active low.
LDAC	3	I	Load DAC. When LDAC is high, no DAC output updates occur when the input digital data is read into the serial interface. The DAC outputs are only updated when LDAC is low.
REFINAB	15	I	Voltage reference input for DAC A and B
REFINCD	10	I	Voltage reference input for DAC C and D
SCLK	5	I	Serial clock input
OUTA	14	0	DAC A
OUTB	13	0	DAC B
OUTC	12	0	DAC C
OUTD	11	0	DAC D

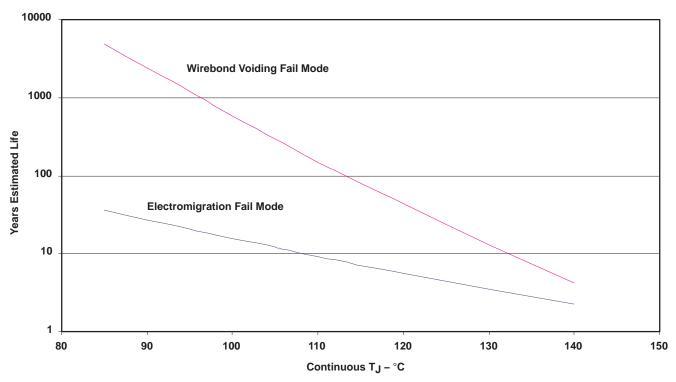


Figure 1. Operating Life Derating Chart



TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3-μs QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, (DV _{DD} , AV _{DD} to GND)	7 V
Supply voltage difference (AV _{DD} to DV _{DD})	2.8 V to 2.8 V
Digital input voltage range	\dots -0.3 V to DV _{DD} + 0.3 V
Reference input voltage range	\dots -0.3 V to AV _{DD} + 0.3 V
Operating free-air temperature range, T _A	–55°C to 125°C
Storage temperature range, T _{stq}	65°C to 150°C
Lead temperature 1,6 mm (1/16 in) from case for 10 s	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Constitution AV BV	5-V supply	4.5	5	5.5	.,
Supply voltage, AV _{DD} , DV _{DD}	3-V supply	2.7	3	3.3	V
High level digital input values V	DV _{DD} = 2.7 V	2			.,
High-level digital input voltage, V _{IH}	DV _{DD} = 5.5 V	2.4			V
Law law later the transfer on M	DV _{DD} = 2.7 V			0.6	.,
Low-level digital input voltage, V _{IL}	DV _{DD} = 5.5 V			1	V
Defendance V. to DEFINAD DEFINOD tourise!	5-V supply, See Note 1	0	2.048	V _{DD} – 1.5	.,
Reference voltage, V _{ref} to REFINAB, REFINCD terminal	3-V supply, See Note 1	0	1.024	V _{DD} – 1.5	V
Load resistance, R _L		2	10		kΩ
Load capacitance, C _L				100	pF
Serial clock rate, SCLK				20	MHz
Operating free-air temperature	-55		125	°C/W	
Package thermal resistance, junction to ambient, θ_{JA}			108.4		°C/W

NOTE 1: Voltages greater than AV_{DD}/2 cause output saturation for large DAC codes.



TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3-us QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range, V_{ref} = 2.048 V, $AV_{DD} = DV_{DD} = 5 \text{ V}$ and $V_{ref} = 1.024 \text{ V}$ for $AV_{DD} = DV_{DD} = 3 \text{ V}$ (unless otherwise noted)

static DAC specifications

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			12			bits
	Integral nonlinearity (INL), end p	ooint adjusted	See Note 1		±1.5	±4	LSB
	Differential nonlinearity (DNL)		See Note 2		±0.5	±1	LSB
EZS	Zero-scale error (offset error at	zero scale)	See Note 3			±12	mV
	Zero-scale error temperature co	efficient	See Note 4		10		ppm/°C
EG	Gain error		See Note 5			±0.7	% of FS voltage
	Gain-error temperature coefficie	ent	See Note 6		10		ppm/°C
DODD	Danier annah mala etter meta	Zero scale	One Mate 7 and Mate 9		-80		dB
	Power-supply rejection ratio	Full scale	See Note 7 and Note 8		-80		dB

- NOTES: 1. The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.
 - 2. The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1-LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.
 - 3. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.
 - 4. Zero-scale-error temperature coefficient is given by: E_{ZS} $TC = [E_{ZS} (T_{max}) E_{ZS} (T_{min})E/V_{ref} \times 10^6/(T_{max} T_{min}).$
 - 5. Gain error is the deviation from the ideal output (2 V_{ref} 1 LSB) with an output load of 10 k Ω , excluding the effects of the zero error.

 6. Gain temperature coefficient is given by: EG TC = [EG(T_{max}) EG (T_{min})]/V_{ref} × 10⁶/(T_{max} T_{min}).

 - 7. Zero-scale-error rejection ratio (EZS-RR) is measured by varying the AVDD from 5 ± 0.5 V and 3 ± 0.3 V dc, and measuring the proportion of this signal imposed on the zero-code output voltage.
 - 8. Full-scale rejection ratio (EG-RR) is measured by varying the AVDD from 5 ± 0.5 V and 3 ± 0.3 V dc and measuring the proportion of this signal imposed on the full-scale output voltage after subtracting the zero-scale change.

individual DAC output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vo	Voltage output range	$R_L = 10 \text{ k}\Omega$	0		AV _{DD} -0.4	V
	Output load regulation accuracy	$R_L = 2 \text{ k}\Omega \text{ vs } 10 \text{ k}\Omega$		0.1	0.25	% of FS voltage

reference inputs (REFINAB, REFINCD)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
٧ı	Input voltage range	See Note 1		0		AV _{DD} -1.5	V
R _I	Input resistance				10		$M\Omega$
Cl	Input capacitance				5		pF
	Reference feed through	REFIN = 1 Vpp at 1 kHz + 1.024 Vdc (see Note 2)			-75		dB
5 () () () ()		BEEN COV COCCUI			0.5		N 41 1-
	Reference input bandwidth	REFIN = 0.2 Vpp + 1.024-Vdc large signal Fast			1		MHz

NOTES: 1. Reference input voltages greater than VDD/2 cause output saturation for large DAC codes.

2. Reference feedthrough is measured at the DAC output, with an input code = 000 hex and a Vref (REFINAB or REFINCD) input = 1.024 Vdc + 1 Vpp at 1 kHz.



TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3-μs QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range, V_{ref} = 2.048 V, AV_{DD} = DV_{DD} = 5 V and V_{ref} = 1.024 V for AV_{DD} = DV_{DD} = 3 V (unless otherwise noted) (continued)

digital inputs (DIN, $\overline{\text{CS}}$, $\overline{\text{LDAC}}$, $\overline{\text{PD}}$)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lн	High-level digital input current	$V_I = V_{DD}$			±1	μΑ
I _I L	Low-level digital input current	V _I = 0 V			±1	μΑ
Cl	Input capacitance			3		pF

power supply

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
PARAMETER 5-V supply, No load, Clock running, All inputs 0 V or V _{DD} 3-V supply, No load, Clock running, All inputs 0 V or DV _{DD}			Slow		1.6	2.4	
	Fast		3.8	5.6			
	Power-supply current		Slow		1.2	1.8	mA
		_	Fast		3.2	4.8	
	Power-down supply current (see Figure 13)		·		10	·	nA

analog output dynamic performance

	PARAMETER	TEST CONDITION	NS	TYP	UNIT
0.0	Output show not	$C_L = 100 \text{ pF}, R_L = 10 \text{ k}Ω,$	Fast	5	V/μs
SR	Output slew rate	$V_O = 10\%$ to 90%, $V_{ref} = 2.048 \text{ V}, 1024 \text{ V}$	Slow	1	V/μs
t _S O	Output autilian Cara	To ±0.5 LSB, C _L = 100 pF,	Fast	3	_
	Output settling time	$R_L = 10 \text{ k}\Omega$, See Note 1	Slow	9	μs
	Output colling for a college	To ±0.5 LSB, C _L = 100 pF,	Fast	1	_
ts(c)	Output settling time, code to code	$R_L = 10 \text{ k}\Omega$, See Note 2	Slow	2	μs
	Glitch energy	Code transition from 7FF to 800		10	nV-s
SNR	Signal-to-noise ratio	Sine ways generated by DAC		74	dB
S/(N+D)	Signal-to-noise + distortion	Sine wave generated by DAC, Reference voltage = 1.024 at 3 V a	and 2.048 at 5 V.	66	dB
THD	Total harmonic distortion	f _S = 400 KSPS, f _{OUT} = 1.1-kHz si	ne wave,	-68	dB
SFDR	Spurious-free dynamic range	$C_L = 100 \text{ pF}, R_L = 10 \text{ k}\Omega, BW = 20$) kHz	70	dB

- NOTES: 1. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of FFF hex to 080 hex for 080 hex to FFF hex.
 - 2. Settling time is the time for the output signal to remain within ± 0.5 LSB of the final measured value for a digital input code change of one count.



electrical characteristics over recommended operating free-air temperature range, V_{ref} = 2.048 V, AV_{DD} = DV_{DD} = 5 V and V_{ref} = 1.024 V for AV_{DD} = DV_{DD} = 3 V (unless otherwise noted) (continued)

digital input timing requirements

		MIN	NOM	MAX	UNIT
t _{su(CS-FS)}	Setup time, CS low before FS↓	10			ns
t _{su(FS-CK)}	Setup time, FS low before first negative SCLK edge	8			ns
t _{su(C16-FS)}	Setup time, sixteenth negative SCLK edge after FS low on which bit D0 is sampled before rising edge of FS	10			ns
tsu(C16-CS)	Setup time. The first positive SCLK edge after D0 is sampled before \overline{CS} rising edge. If FS is used instead of the SCLK positive edge to update the DAC, then the setup time is between the FS rising edge and \overline{CS} rising edge.	10			ns
t _{wH}	Pulse duration, SCLK high	25			ns
t _{wL}	Pulse duration, SCLK low	25			ns
t _{su(D)}	Setup time, data ready before SCLK falling edge	8			ns
th(D)	Hold time, data held valid after SCLK falling edge	5			ns
twH(FS)	Pulse duration, FS high		60		ns

PARAMETER MEASUREMENT INFORMATION

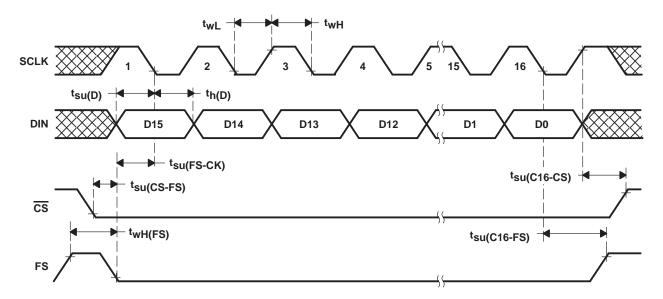


Figure 2. Timing Diagram



TYPICAL CHARACTERISTICS

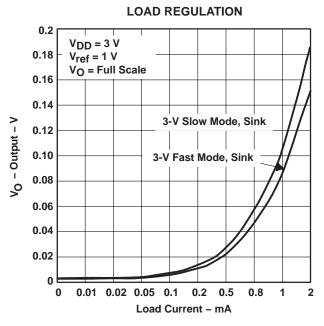


Figure 3

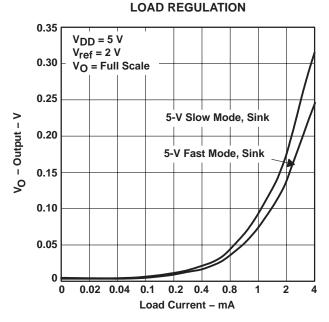


Figure 4

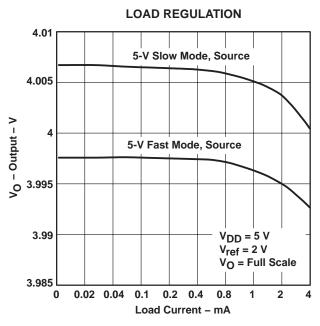


Figure 5

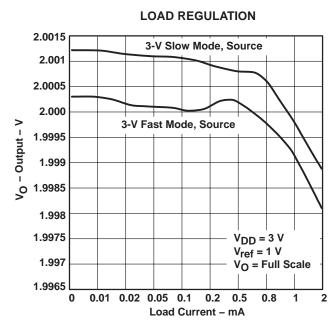
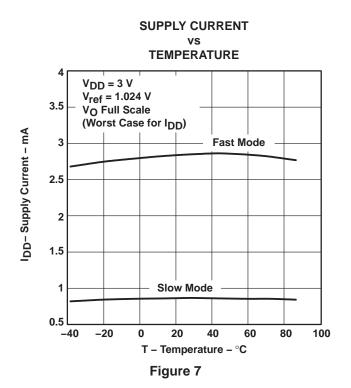
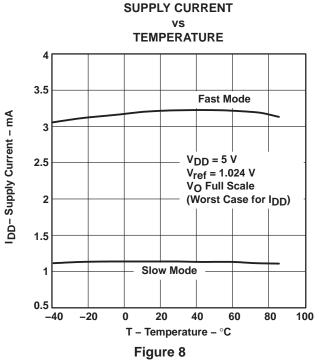


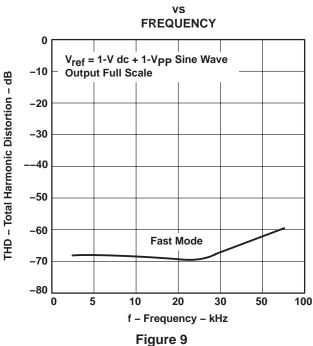
Figure 6

TYPICAL CHARACTERISTICS









vs **FREQUENCY** 0 V_{ref} = 1-V dc + 1-V_{PP} Sine Wave -10 Output Full Scale THD - Total Harmonic Distortion - dB -20 -30 --40 -50 -60 **Slow Mode** -70 -80 5 100

f - Frequency - kHz

Figure 10

TOTAL HARMONIC DISTORTION

TYPICAL CHARACTERISTICS

TOTAL HARMONIC DISTORTION AND NOISE **FREQUENCY** 0 THD - Total Harmonic Distortion And Noise - dB Vref = 1-V dc + 1-Vpp Sine Wave -10 Output Full Scale -20 -30 --40 -50 **Fast Mode** -60 -70 -80 5 10 50 100 0 f - Frequency - kHz

FREQUENCY

O
Vref = 1-V dc + 1-Vpp Sine Wave,
Output Full Scale

-20
-30
-30
-50
Slow Mode
-60
-70
-70

TOTAL HARMONIC DISTORTION AND NOISE

Figure 11

Figure 12

10

20

f - Frequency - kHz

30

50

100

SUPPLY CURRENT

-80

5

٧S TIME (WHEN ENTERING POWER-DOWN MODE) 4000 3500 3000 IDD - Supply Current - µA 2500 2000 1500 1000 500 0 200 800 0 400 600 1000 t - Time - ns



Figure 13

TYPICAL CHARACTERISTICS

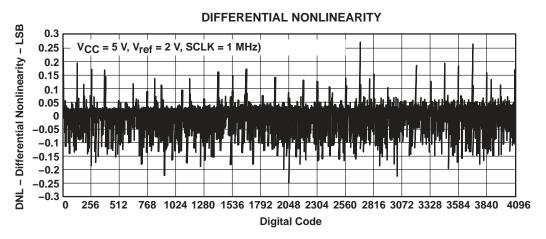


Figure 14

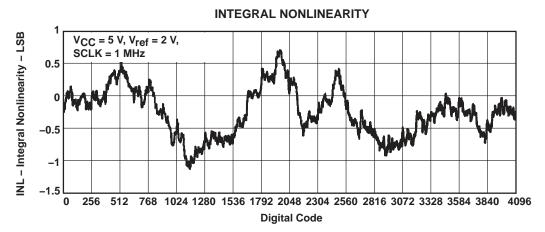


Figure 15



APPLICATION INFORMATION

general function

The TLV5614 is a 12-bit single-supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power-down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

$$2 REF \frac{CODE}{2^n} [V]$$

where REF is the reference voltage and CODE is the digital input value within the range of 0_{10} to 2^n –1, where n = 12 (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data* format section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

serial interface

Explanation of data transfer: First, the device has to be enabled with \overline{CS} set to low. Then, a falling edge of FS starts shifting the data bit per bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch, which updates the voltage output to the new level.

The serial interface of the TLV5614 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four-wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320 DSP family. Figure 16 shows an example with two TLV5614s connected directly to a TMS320 DSP.

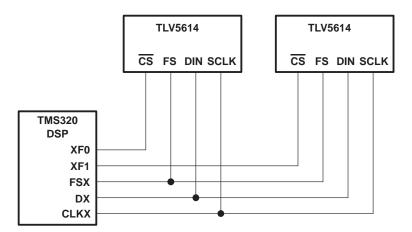


Figure 16. TMS320™ Interface

TMS320 is a trademark of Texas Instruments.



APPLICATION INFORMATION

serial interface (continued)

If there is no need to have more than one device on the serial bus, then \overline{CS} can be tied low. Figure 17 shows an example of how to connect the TLV5614 to a TMS320, SPI, or Microwire port using only three pins.

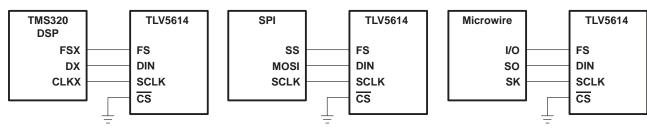


Figure 17. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5614. After the write operation(s), the DAC output is updated automatically on the next positive clock edge, following the sixteenth falling clock edge.

serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{WH(min)} + t_{WL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16 \left(t_{wH(min)} + t_{wL(min)}\right)} = 1.25 \text{ MHz}$$

Note that the maximum update rate is a theoretical value for the serial interface, since the settling time of the TLV5614 has to be considered also.

data format

The 16-bit data word for the TLV5614 consists of two parts:

Control bits (D15...D12)
 New DAC value (D11...D0)

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
A1	A0	PWR	SPD					Nev	v DAC va	alue (12 b	oits)				

X: Don't care

SPD: Speed control bit: $1 \rightarrow \text{fast mode}$ $0 \rightarrow \text{slow mode}$ PWR: Power control bit: $1 \rightarrow \text{power down}$ $0 \rightarrow \text{normal operation}$

APPLICATION INFORMATION

data format (continued)

In power-down mode, all amplifiers within the TLV5614 are disabled. A particular DAC (A, B, C, D) of the TLV5614 is selected by A1 and A0 within the input word.

A1	A0	DAC
0	0	А
0	1	В
1	0	С
1	1	D

TLV5614 interfaced to TMS320C203 DSP

hardware interfacing

Figure 18 shows an example of how to connect the TLV5614 to a TMS320C203 DSP. The serial port is configured in burst mode, with FSX generated by the TMS320C203 to provide the frame synchronization (FS) input to the TLV5614. Data is transmitted on the DX line, with the serial clock input on the CLKX line. The general-purpose input/output port bits, IO0 and IO1, are used to generate the chip select (\overline{CS}) and DAC latch update (\overline{LDAC}) inputs to the TLV5614. The active-low power down (\overline{PD}) is pulled high all the time to ensure the DACs are enabled.

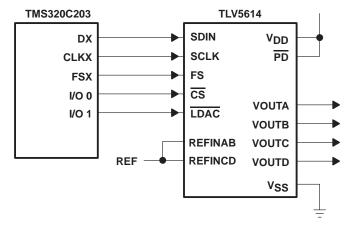


Figure 18. TLV5614 Interfaced With TMS320C203

software

The application example outputs a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal as the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses LDAC low to update all four DACs simultaneously, then fetches and writes the next sample to all four DACs. The samples are stored in a look-up table, which describes two full periods of a sine wave.

The synchronous serial port of the DSP is used in burst mode. In this mode, the processor generates an FS pulse preceding the MSB of every data word. If multiple, contiguous words are transmitted, a violation of the $t_{su}(C16-FS)$ timing requirement occurs. To avoid this, the program waits until the transmission of the previous word has been completed.



```
; Processor: TMS320C203 running at 40 MHz
; Description:
; This program generates a differential in-phase (sine) on (OUTA-OUTB) and it's
; quadrature (cosine) as a differential signal on (OUTC-OUTD).
; The DAC codes for the signal samples are stored as a table of 64 12-bit values,
; describing 2 periods of a sine function. A rolling pointer is used to address the
; table location in the first period of this waveform, from which the DAC A samples
; are read. The samples for the other 3 DACs are read at an offset to this rolling
; pointer:
       Function sine
                  Offset from rolling pointer 0
  DAC
   Α
        inverse sine 16
  C
D
       cosine 8 inverse cosine24
; The on-chip timer is used to generate interrupts at a fixed rate. The interrupt ; service routine first pulses LDAC low to update all DACs simultaneously
; with the values which were written to them in the previous interrupt. Then all
; 4 DAC values are fetched and written out through the synchronous serial interface
; Finally, the rolling pointer is incremented to address the next sample, ready for ; the next interrupt.
; © 1998, Texas Instruments Inc.
;-----
   ----- I/O and memory mapped regs -----
      .include "regs.asm"
  -----jump vectors -----
      .ps Oh
      b
          start
int1
      b
     b int23
b timer_isr;
----- variables ------
iosr_stat .equ 0062h
DACa_ptr .equ 0063h
DACb_ptr .equ 0064h
DACc_ptr .equ 0065h
DACd_ptr .equ 0066h
;-----constants-----
; DAC control bits to be OR'ed onto data
; all fast mode
DACa_control .equ
                 01000h
DACb_control .equ 05000h
DACc_control .equ 09000h
DACd_control .equ 0d000h
;---- tables -----
  .ds 02000h
sinevals
  .word 00800h
   .word 0097Ch
   .word 00AE9h
   .word 00C3Ah
   .word 00D61h
   .word 00E53h
   .word 00F07h
   .word 00F76h
   .word 00F9Ch
   .word 00F76h
   .word 00F07h
   .word 00E53h
```



TLV5614-EP 2.7-V TO 5.5-V 12-BIT 3-μs QUADRUPLE DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN SGLS355 – JUNE 2006

.word	00D61h
.word	00C3Ah
.word	00AE9h
.word	0097Ch
.word	00800h
.word	00684h
.word	00517h
.word	003C6h
.word	0029Fh
.word	001ADh
.word	000F9h
.word	0008Ah
.word	00064h
.word	0008Ah
.word	0000An
.word	001ADh
.word	0029Fh
.word	003C6h
.word	00517h
.word	00684h
.word	00800h
.word	0097Ch
.word	00AE9h
.word	00C3Ah
	00C3An
.word	
.word	00E53h
.word	00F07h
.word	00F76h
.word	00F9Ch
.word	00F76h
.word	00F07h
.word	00E53h
.word	00D61h
.word	00C3Ah
.word	00AE9h
.word	0097Ch
.word	00800h
.word	00684h
.word	00517h
.word	003C6h
.word	0029Fh
.word	001ADh
.word	000F9h
.word	000F3H
.word	00064h
.word	0008Ah
.word	000F9h
.word	001ADh
.word	0029Fh
.word	003C6h
.word	00517h
.word	00684h
. word	0000411



```
; Main Program
      .ps 1000h
      .entry
start
; disable interrupts
      setc INTM
                   ; disable maskable interrupts
             #Offffh, IFR; clear all interrupts
      splk #0004h, IMR; timer interrupts unmasked
;-----
; set up the timer
; timer period set by values in PRD and TDDR
; period = (CLKOUT1 period) x (1+PRD) x (1+TDDR)
; examples for TMS320C203 with 40MHz main clock
; Timer rate TDDR PRD; 80 kHz 9 24 (18h); 50 kHz 9 39 (27h)
;-----
prd_val.equ 0018h
tcr_val.equ 0029h
tcr_val.equ
      splk #0000h, temp; clear timer
            temp, TIM
      out
      splk #prd_val, temp; set PRD
             temp, PRD
      out
             #tcr_val, temp; set TDDR, and TRB=1 for auto-reload
      splk
          temp, TCR
; Configure IOO/1 as outputs to be :
; IOO CS - and set high
; IO1 LDAC - and set high
           temp, ASPCR; configure as output
      in
      lacl temp
      or #0003h
sacl temp
      out temp, ASPCR
            temp, IOSR; set them high
      in
      lacl temp
      or
            #0003h
      sacl temp
      out temp, IOSR
; set up serial port for
; SSPCR.TXM=1 Transmit mode - yenerace 1.
• SSPCR.MCM=1 Clock mode - internal clock source
      splk #0000Eh, temp
           temp, SSPCR; reset transmitter
      out
      splk #0002Eh, temp
      out temp, SSPCR
; reset the rolling pointer
     lacl #000h
; enable interrupts
     clrc INTM ; enable maskable interrupts
; loop forever!
```



```
next
      idle
                      ; wait for interrupt
      b
            next
;-----
; all else fails stop here
:-----
done b done ; hang there
; Interrupt Service Routines
int1 ret ; do nothing and return int23 ret ; do nothing and return
              ; do nothing and return
timer isr:
        iosr_stat, IOSR; store IOSR value into variable space
  in
         iosr_stat ; load acc with iosr status
   lacl
                      ; reset IO1 - LDAC low
         #0FFFDh
  and
         temp
temp, IOSR
   sacl
   out
                      ; set IO1 - LDAC high
  or
         #0002h
   sacl
         temp
         temp, IOSR
   out
   and
         #0FFFEh
                      ; reset IOO - CS low
   sacl
         temp
        temp, IOSR
   out
                      ; load rolling pointer to accumulator
   lacl
         r ptr
                      ; add pointer to table start
         #sinevals
   add
   sacl
         DACa_ptr
                     ; to get a pointer for next DAC a sample
                     ; add 8 to get to DAC C pointer
   add
         #08h
         DACc_ptr
   sacl
                      ; add 8 to get to DAC B pointer
   add
         #08h
         DACb_ptr
   sacl
  add
         #08h
                      ; add 8 to get to DAC D pointer
   sacl
         DACd ptr
         *,ar0
  mar
                      ; set ar0 as current AR
   ; DAC A
   lar
         ar0, DACa ptr; ar0 points to DAC a sample
         * ; get DAC a sample into accumulator #DACa_control; OR in DAC A control bits
   lacl
   or
   sacl
         temp, SDTR
  out
                    ; send data
; We must wait for transmission to complete before writing next word to the SDTR.;
TLV5614/04 interface does not allow the use of burst mode with the full packet; rate, as
we need a CLKX -ve edge to clock in last bit before FS goes high again,; to allow SPI
compatibility.
               ; wait long enough for this configuration
  rpt
         #016h
                      ; of MCLK/CLKOUT1 rate
  nop
   ; DAC B
         ar0, dacb_ptr; ar0 points to DAC a sample
   lar
                     ; get DAC a sample into accumulator
   lacl
         #DACb_control; OR in DAC B control bits
   or
   sacl
         temp
         temp, SDTR
                      ; send data
   out
                      ; wait long enough for this configuration
   rpt
         #016h
                      ; of MCLK/CLKOUT1 rate
  nop
; DAC C
         ar0, dacc_ptr; ar0 points to dac a sample
   lar
                      ; get DAC a sample into accumulator
   lacl
         #DACc control; OR in DAC C control bits
   or
   sacl
            temp
   out
            temp, SDTR; send data
                    ; wait long enough for this configuration
  rpt
            #016h
                      ; of MCLK/CLKOUT1 rate
```

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```
; DAC D
         lar
   lacl
  or
  sacl
         temp
         temp, SDTR
                    ; send data
  out
                     ; load rolling pointer to accumulator
  lacl
         r ptr
  add
         #<u>1</u>h
                     ; increment rolling pointer
                     ; count 0-31 then wrap back round
         #001Fh
  and
                     ; store rolling pointer; wait long enough for this configuration; of MCLK/CLKOUT1 rate
  sacl
         r ptr
         #016h
  rpt
  nop
; now take CS high again
  lacl iosr_stat ; load acc with iosr status
                     ; set IOO - CS high
         #000<u>1</u>h
  or
        temp
  sacl
  out
         temp, IOSR
                     ; re-enable interrupts
        intm
  clrc
  ret
                      ; return from interrupt
.end
```



APPLICATION INFORMATION

TLV5614 interfaced to MCS®51 microcontroller

hardware interfacing

Figure 19 shows an example of how to connect the TLV5614 to an MCS $^{\circledR}$ 51 Microcontroller. The serial DAC input data and external control signals are sent via I/O port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the TxD line. Port 3 bits 3, 4, and 5 are configured as outputs to provide the DAC latch update ($\overline{\text{LDAC}}$), chip select ($\overline{\text{CS}}$) and frame sync (FS) signals for the TLV5614. The active low power down pin ($\overline{\text{PD}}$) of the TLV5614 is pulled high to ensure that the DACs are enabled.

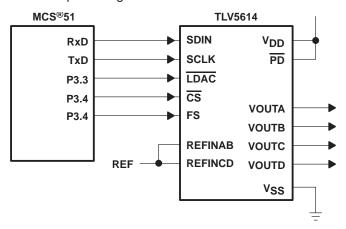


Figure 19. TLV5614 Interfaced With MCS®51

software

The example is the same as for the TMS320C203 in this data sheet, but adapted for a MCS[®]51 controller. It generates a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal is the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses LDAC low to update all four DACs simultaneously, then fetches and writes the next sample to all four DACs. The samples are stored as a look-up table, which describes one full period of a sine wave.

The serial port of the controller is used in Mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes, concatenated together, are required to write a complete word to the TLV5614. The $\overline{\text{CS}}$ and FS signals are provided in the required fashion through control of IO port 3, which has bit addressable outputs.



```
; Processor: 80C51
; Description:
; This program generates a differential in-phase
(sine) on (OUTA-OUTB); and it's quadrature (cosine)
as a differential signal on (OUTC-OUTD).
; © 1998, Texas Instruments Inc.
NAME GENIQ
               CODE
MAIN SEGMENT
      SEGMENT
                 CODE
SINTBL SEGMENT
                 CODE
              DATA
IDATA
VAR1 SEGMENT
STACK SEGMENT
; Code start at address 0, jump to start
  CSEG AT 0
  LJMP start
                    ; Execution starts at address 0 on power-up.
,_____<del>-</del>
; Code in the timerO interrupt vector
;------
  CSEG AT 0BH
                   ; Jump vector for timer 0 interrupt is 000Bh
  LJMP timer0isr
; Global variables need space allocated
  RSEG VAR1
temp ptr: DS
                 1
rolling ptr: DS
Interrupt service routine for timer 0 interrupts
  RSEG
timer0isr:
  PUSH
           PSW
           ACC
   PUSH
  CLR
            INT1
                     ; pulse LDAC low
                     ; to latch all 4 previous values at the same time
  SETB
           INT1
                    ; 1st thing done in timer isr => fixed period
  CLR
       T0
                     ; set CS low
   ; The signal to be output on each DAC is a sine function.
   ; One cycle of a sine wave is held in a table @ sinevals
   ; as 32 samples of msb, lsb pairs (64 bytes).
   ; We have ; one pointer which rolls round this table, rolling ptr,
   ; incrementing by 2 bytes (1 sample) on each interrupt (at the end of
   ; this routine).
   ; The DAC samples are read at an offset to this rolling pointer:
   ; DAC Function Offset from rolling ptr
     A
        sine
        inverse sine 32
     В
     C
         cosine
                     16
   ;
        inverse cosine48
  VOM
        DPTR, #sinevals; set DPTR to the start of the table
        ; of sine signal values R7,rolling_ptr; R7 holds the pointer
  VOM
                     ; into the sine table
       A,R7 ; get DAC A msb
A,@A+DPTR ; msb of DAC A is in the ACC
  VOM
  MOVC
```



```
; transmit it - set FS low
   CLR
   MOV
          SBUF,A
                        ; send it out the serial port
   INC
                        ; increment the pointer in R7
                       ; to get the next byte from the table
          A,R7
   MOV
   MOVC
          A,@A+DPTR
                       ; which is the lsb of this sample, now in ACC
   A MSB TX:
                       ; wait for transmit to complete
   JNB
          TI,A MSB TX
          ΤI
                       ; clear for new transmit
   MOV
          SBUF, A
                       ; and send out the 1sb of DAC A
   ; DAC C next
   ; DAC C codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives a cosine function
                       ; pointer in R7
         A,R7
   ADD
          A,#OFH
                       ; add 15 - already done one INC
                       ; wrap back round to 0 if > 64
             A,#03FH
   ANL
          R7,A
   MOV
                       ; pointer back in R7
   MOVC
        A,@A+DPTR
                       ; get DAC C msb from the table
   ORL
          A,#01H
                        ; set control bits to DAC C address
A LSB TX:
   TNB
          TI,A_LSB_TX
                       ; wait for DAC A lsb transmit to complete
   SETB
                       ; toggle FS
   CLR T1
   CLR
                       ; clear for new transmit
                       ; and send out the msb of DAC C
   MOV
          SBUF, A
   INC
          R7
                       ; increment the pointer in R7
          A,R7
                       ; to get the next byte from the table
   MOV
   MOVC
         A,@A+DPTR
                       ; which is the lsb of this sample, now in ACC
C MSB TX:
          TI, C MSB TX ; wait for transmit to complete
                       ; clear for new transmit
   CLR
          TТ
   MOV
          SBUF, A
                       ; and send out the 1sb of DAC C
   ; DAC B next
   ; DAC B codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives an inverted sine function
   VOM
                       ; pointer in R7
                      ; add 15 - already done one INC
; wrap back round to 0 if > 64
   ADD
            A,#0FH
   ANL
          A,#03FH
                       ; pointer back in R7
   MOV
         R7,A
   MOVC
        A,@A+DPTR
                       ; get DAC B msb from the table
             A,#02H
                       ; set control bits to DAC B address
   ORL
C LSB TX:
          TI,C_LSB_TX
                       ; wait for DAC C lsb transmit to complete
   TNB
   SETB
          T1
                        ; toggle FS
   CLR
          T1
   CLR
          ΤТ
                        ; clear for new transmit
          SBUF, A
   MOV
                        ; and send out the msb of DAC B
    get DAC B LSB
                       ; increment the pointer in R7
   INC
         R7
   MOV
          A,R7
                       ; to get the next byte from the table
         A,@A+DPTR
                       ; which is the lsb of this sample, now in ACC
   MOVC
B MSB TX:
                       ; wait for transmit to complete
   \overline{\mathsf{JNB}}
          TI,B MSB TX
                       ; clear for new transmit
   CLR
          TТ
             SBUF,A
                       ; and send out the 1sb of DAC B
   MOV
   ; DAC D codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives an inverted cosine function
```



```
MOV
           A,R7
                           ; pointer in R7
         A,#0FH
                           ; add 15 - already done one INC
   ADD
              A,#03FH ; wrap back round to 0 if > 64
    ANL
         R7,A ; pointer back in R7
A,@A+DPTR ; get DAC D msb from the table
A,#03H ; set control bits to DAC D address
   MOV
   MOVC
   ORL
B_LSB TX:
   \overline{\mathtt{JNB}}
           TI,B LSB TX ; wait for DAC B lsb transmit to complete
           T1
                         ; toggle FS
    SETB
   CLR
           Т1
           TI ; clear for new transmit
MOV SBUF, A
                          ; and send out the msb of DAC D
          R7 ; increment the pointer in R7
A,R7 ; to get the next byte from the table
A,@A+DPTR ; which is the lsb of this sample, now in ACC
   TNC
   VOM
   MOVC
D MSB TX:
           TI,D MSB TX ; wait for transmit to complete
                    ; clear for new transmit
           TI
   CLR
   MOV
           SBUF,A
                           ; and send out the 1sb of DAC D
    ; increment the rolling pointer to point to the next sample
    ; ready for the next interrupt
           A,rolling_ptr
   MOV
                      ; add 2 to the rolling pointer
; wrap back round to 0 if > 64
   ADD
           A,#02H
   ANL
           A,#03FH
   MOV
           rolling ptr, A; store in memory again
D LSB TX:
           TI,D_LSB_TX ; wait for DAC D lsb transmit to complete TI ; clear for next transmit T1 ; FS high
   JNB
    CLR
   SETB
                          ; CS high
           TΩ
   POP
           ACC
   POP
           PSW
   RETI
; Stack needs definition
   RSEG STACK
                           ; 16 Byte Stack!
   DS 10h
 ______
; Main program code
   RSEG MAIN
start:
           SP,#STACK-1 ; first set Stack Pointer
   MOV
          SCON,A ; set serial port 0 to mode 0
TMOD,#02H ; set timer 0 to mode 2 - auto-reload
THO,#038H ; set THO for 5kHs interrupts
INT1 ; set LDAC = 1
T1 ; set FS = 1
T0 ; set CS = 1
ETO ; enable timer 0 interrupts
EA ; enable all interrupts
rolling ptr,A; set rolling pointer to 0
    CLR A
   MOV
   MOV
   MOV
    SETB
    SETB
   SETB
    SETB
    SETB
           rolling_ptr,A; set rolling pointer to 0
   VOM
                       ; start timer 0
   SETB
always:
   SJMP
           always
                          ; while(1) !
;------
; Table of 32 sine wave samples used as DAC data
   RSEG SINTBL
```



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sineval	ls:
DW	01000H
DW	0903EH
DW	05097H
DW	0305CH
DW	0B086H
DW	070CAH
DW	OFOEOH
DW	0F06EH
DW	0F039H
DW	0F06EH
DW	OFOEOH
DW	070CAH
DW	0B086H
DW	0305CH
DW	05097H
DW	0903EH
DW	01000H
DW	06021H
DW	0A0E8H
DW	0C063H
DW	040F9H
DW	080B5H
DW	0009FH
DW	00051H
DW	00026H
DW	00051H
DW	0009FH
DW	080B5H
DW	040F9H
DW	0C063H
DW	0A0E8H
DW	06021H
END	



PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

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Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV5614MPWREP	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	5614EP	Samples
V62/06602-01XE	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	5614EP	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

10-Dec-2020

OTHER QUALIFIED VERSIONS OF TLV5614-EP:

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NOTE: Qualified Version Definitions:

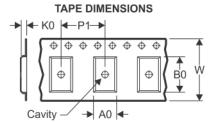
• Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 12-Feb-2019

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5614MPWREP	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 12-Feb-2019



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TLV5614MPWREP	TSSOP	PW	16	2000	350.0	350.0	43.0	



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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